Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/689,245	KELLEHER, DAVID WAYNE	
Examiner	Art Unit	
Khawar Igbal	2686	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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